



Product Change Notification / MFOL-07PXJU937

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**Date:**

09-May-2023

**Product Category:**

Memory

**PCN Type:**

Manufacturing Change

**Notification Subject:**

CCB 6233 Final Notice: Qualification of 95x155 mils leadframe paddle size for selected AT25512 and AT25M01 device families available in 8L SOIC (3.90mm) package at ANAP assembly site.

**Affected CPNs:**

[MFOL-07PXJU937\\_Affected\\_CPN\\_05092023.pdf](#)  
[MFOL-07PXJU937\\_Affected\\_CPN\\_05092023.csv](#)

**Notification Text:**

**PCN Status:**Final Notification

**PCN Type:**Manufacturing Change

**Microchip Parts Affected:**Please open one of the files found in the Affected CPNs section.  
Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

**Description of Change:**Qualification of 95x155 mils leadframe paddle size for selected AT25512 and AT25M01 device families available in 8L SOIC (3.90mm) package at ANAP assembly site.

**Pre and Post Change Summary:**

	Pre Change	Post Change
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Assembly Site	Amkor Technology Philippine (P1/P2), INC.  (ANAP)	Amkor Technology Philippine (P1/P2), INC.  (ANAP)
Wire Material	PdCu/Au	PdCu/Au
Die Attach Material	8290	8290
Molding Compound Material	G700A/G600	G700A/G600
Lead-Frame Material	C194	C194
Lead-Frame Paddle Size	90x130 mils	95x155 mils
	See Pre and Post change comparison.	

**Impacts to Data Sheet:**None

**Change Impact:**None

**Reason for Change:**To improve manufacturability by qualifying 95x155 mils leadframe paddle size at ANAP assembly site.

**Change Implementation Status:**In Progress

**Estimated First Ship Date:**May 31, 2023 (date code: 2322)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Time Table Summary:**

	May 2023				
	1 8	1 9	2 0	2 1	2 2
Qual Report Availability		x			
Final PCN Issue Date		x			
Estimated Implementation Date					x

**Method to Identify Change:**Traceability code

**Qualification Report:**Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report.

**Revision History:**May 09, 2023: Issued final notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

### **Attachments:**

[PCN\\_MFOL-07PXJU937\\_Pre and Post Summary.pdf](#)  
[PCN\\_MFOL-07PXJU937\\_Qual Report.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



**MICROCHIP**  
**QUALIFICATION REPORT SUMMARY**

**PCN ID#: MFOL-07PXJU937**

**Date:**  
**April 13, 2022**

**Qualification of 95x155 mils leadframe paddle size for selected AT25512 and AT25M01 device families available in 8L SOIC (3.90mm) package at ANAP assembly site.**

**Purpose:** Qualification of 95x155 mils leadframe paddle size for selected AT25512 and AT25M01 device families available in 8L SOIC (3.90mm) package at ANAP assembly site.

**CCB No:** 4406 and 6233

## I. Summary

This report summarizes the results of stresses performed on the 8L-SOIC using 358A173BXC06 / AT25128B-SSHL (35.8k technology) with cu-wire (CuPdAu) assembled at Amkor / ANAP. These assembly lots were processed through the entire production package assembly process and stressed to the package qualification guidelines established in Microchip specification QCI-39000 at a Moisture/Reflow Sensitivity Classification Level 1 (MSL1) at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

**Conclusion** - This report presents data that qualifies the existing industrial products of the 35.xK and 36.xK process in the copper wire 8L-SOIC package of Amkor / ANAP package assembly using masks 358A1, 365S6, 363V2, and 363V4.

## II. Description of Package / Die selected for Qualification

<b>Assembly site</b>	Amkor / ANAP
<b>CPN</b>	AT25128B-SSHL
<b>MPN</b>	358A173BXC06
<b>BD number</b>	w358A1syu, rev. B
<b>Package Pin Count</b>	8
<b>Package Group</b>	SOIC (150 mil wide)
<b>Package Size</b>	3.9x4.9mm
<b>LF PN</b>	101378808
<b>Lead plating</b>	NiPdAu PPF
<b>Paddle Size</b>	90 x 90 mils
<b>LF Material / Surface</b>	C194 / none
<b>Process / Lead Lock</b>	Stamped / no
<b>Die Attach</b>	8290 conductive
<b>Wire</b>	CuPdAu
<b>Mold Compound</b>	G700A

## III. Manufacturing Information

<b>Lot #</b>	<b>Assembly Lot Number</b>	<b>Wafer Lot Number</b>	<b>Date Code</b>
Lot 1	212000226ANAP	9Y0632	2033
Lot 2	202500212ANAP	9W1801	1938
Lot 3	202100219ANAP	9U7116	1934

#### IV. Stress Results

- Unless otherwise noted, electrical testing was performed at +25C, +85°C and +125°C.

#### **MSL1 Moisture Soak Evaluation & Precondition Prior to Stresses**

Test Method	JESD22-A113; IPC/JEDEC J-STD-020
Test Condition	Bake 24 hours at +150°C Soak 85% RH / 168 hours 3x Convection Reflow 260°C
Moisture Reflow Sensitivity Level	1
<b>Moisture Level Evaluation</b>	
Sample Size	50 each lot / 3 lots
Electrical Results (Fail / Pass)	0 / 150
<b>Moisture Soak Precondition Prior to TC / UHST / HAST stresses</b>	
Electrical Results (Fail / Pass)	0 / 738

#### **High Temperature Storage**

Test Method	JESD22-A103
Test Condition	175°C / 1008 hours
Sample Size	50 each lot / 3 lots
Results (Fail / Pass)	0 / 150

#### **Temperature Cycling**

Test Method	JESD22-A104
Test Condition	-65°C / 150°C Air to Air / 1000 Cycles
Sample Size	82 each lot / 3 lots
85°C & 125°C Electrical Results (Fail / Pass)	0 / 246

#### **Unbiased HAST**

Test Method	JESD22-A118
Test Condition	130°C / 85% RH / 192 hours
Sample Size	82 each lot / 3 lots
Unbiased Electrical Results (Fail / Pass)	0 / 246

### Biased HAST

Test Method	JESD22-A110
Test Condition	5.5V / 130°C / 85% RH / 192 hours
Sample Size	82 each lot / 3 lots
Electrical Results (Fail / Pass)	0 / 246

### Wire Pull Post HTS

Test Method	JESD22-B115
Test Condition	> 3 grams
Required Sample Size	30 each lot / 1 lot min
Results (Fail / Pass)	0/30

**CCB 6233**  
**PCN ID#: MFOL-07PXJU937**



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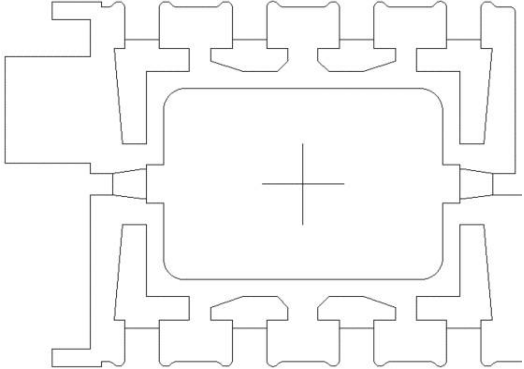
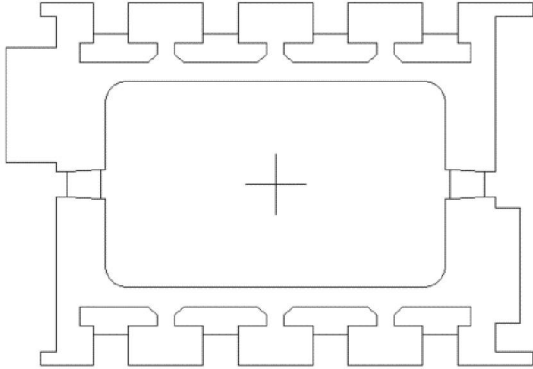
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# Pre and Post Summary – Leadframe drawing/lay-out comparison

ANAP	ANAP
 <p>Leadframe Paddle Size   90x130mils</p>	 <p>Leadframe Paddle Size   95x155mils</p>

Note: Not fit to scale

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Affected Catalog Part Numbers(CPN)

AT25512N-SH-B-899

AT25512N-SH-T-834

AT25512N-SH-T-899

AT25512N-SH-B

AT25512N-SH-T

AT25M01-SSHM-B

AT25M01-SSHM-T